


<b><i>Search Notes</i></b>  	<b>Application/Control No.</b>  10520169	<b>Applicant(s)/Patent Under Reexamination</b>  BACON ET AL.
	<b>Examiner</b>  Shin-Lin Chen	<b>Art Unit</b>  1632

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
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INTERFERENCE SEARCH			
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